GENERAL PROCESS AND OPERATION SPECIFICATION

Oxford Instruments PlasmaLab 80Plus – PECVD Deposition Tool

I. SCOPE

- a. The purpose of this document is to describe requirements and basic operating instructions for the Oxford Instruments Plasmalab 80Plus PECVD. The PECVD tool is intended for plasma-enhanced physical vapor deposition of silicon oxide, silicon nitride or silicon oxy-nitride films over various substrates.
- II. SAFETY
 - a. Be sure that you are trained and signed off to use this equipment.
 - b. Be sure to keep all doors and protective shields in place before operating this equipment.
 - c. Use care when operating around high voltage or high current.
 - d. Use care when operating in RF mode of operation. Avoid coming near any electrodes or conductors carrying RF energy.
 - e. High pressure gas cylinders for this tool are stored in ventilated gas cabinets located in the 7H1 service corridor. Be sure to ask a staff member for assistance to change out any gases.
 - f. A recipe can be aborted at any time by selecting STOP ALL PROCESSES, located in the top right corner of the software display.
 - g. When the chamber is open, do not touch the inside of the chamber or the gas shower head.
 - h. Beware of residual process gases when opening the chamber. Gases such as NH₃, SiH₄ and CF₄ are very toxic. Do not skip the final pump step in deposition or clean recipes.
 - i. If you are unsure about any procedure or indication while operating this equipment be sure to contact a staff member or trainer for assistance.
- III. APPLICABLE DOCUMENTS, MATERIALS AND REQUIREMENTS
 - a. For more information about the detailed operation of this tool refer to the Oxford factory manual – "Plasmalab80Plus Compact Plasma System." File name: Texas A&M 94-219873 System Manual.pdf.
 - b. This tool is intended for a relatively wide range of substrate and target materials.
 - c. This tool is configured to run with the following gases for normal processing: N2, N2O, NH3, SiH4/N2. In addition, O2 and CF4 is available only for running in "clean" mode. Clean mode is not available to regular users and can only be run with manager access.
 - d. Gases are stored in the service corridor, but are available under software recipe control.
 - e. This tool uses a mechanical pump (Leybold-Heraeus D90AC) with an Alcatel Blower RSV 600 to maintain adequate working pressures with relatively high gas flow rates. Ask a staff member for assistance to turn these pumps on or off as needed.

IV. OPERATION

- a. Fill out the PECVD logbook to record a history of materials and process parameters.
- b. Normal operations follow steps described below. The factory manual is available on line, or on the PC for the tool to provide more detailed information.

#	Step	Photo	Note
	Ensure that the vacuum pumps are running – located in service hallway.		Ask staff to turn on the PECVD pump before running.
1	Log in the system by clicking "View Only" or "System->Password"	Oppose PACK Control. Image: State of the state of t	Case sensitive
2	Click "System->Pumping" if pump control is not shown. Click "Stop" to end evacuate	Pumping or venting stopped Lid CLOSED Process interlock OK Cm gauge Vent Time Left O secs EVACUATE © STOP O VENT @	
3	After "Stop" light turn to yellow. Click "Vent" to vent to atmosphere	Trived Charlow Fund	
4	Wait for count down, around 3 minutes until it displayed "Venting finished", the chamber can be opened.	Venting finished Lid CLOSED Process interlock FAULT Cm gauge 2000 mTorr Vent Time Left 0 secs EVACUATE © STOP © 12T 0	

5	To open the chamber, switch the knob to "Chamber Up" position.	Citatistic Course	
6	Put both thumbs on the left and right hoists, press at the same time, chamber will open		
7	Until the chamber is fully opened, place the sample in the middle of the holder plate	Do not touch the holder plate, it may be very hot!!	
8	To close the chamber, switch the knob to "Chamber Down" position. Put both thumbs on the left and right hoists, press at the same time, chamber now will close		
9	 A) Before evacuating the chamber, ensure that the "Soft Pump Time" is > 30 seconds – easier on blower and keeps small samples from moving. B) In the "Pumping" page, click "Stop", then click "Evacuate". 	Venting finished Lid CLOSED Process interlock FAULT Cm gauge 2000 mT or Vent Time Left Disecs EVACUATE STOR VENT O	Pumping or venting stopped Lid CLOSED Process interlock FAULT Cm gauge Vent Time Left Disecs EVACUTE O STOP VENT O

10	Enter wafer name, then click "OK"	Load Water or pump chamber MJC CXFORD Enter Water Name(OK) No Water (CANCEL) A5:	
11	Evacuating, wait until display "Base pressure reach"	Evacuating Chamber Lid Process interlock Com gauge Vent Time Left Evacuate O stop O rear O	Base pressure reached Lid CLOSED Process interlock OK Cm gauge 42 mTor Vent Time Left 0 secs EVACUATE STOP VENT O
12	Click "Process"-> "Recipes"		Load Process recipes for viewing and selection. If only "clean" recipes are visible, then the tool is still in clean mode. Contact a staff person to return the tool to normal mode.
13	Edit current recipe or click "Load" to load old recipes.	Load Recipe Recipe Hame Si Dioxide Deposition PROD TEST Si Dioxide Deposition Si deposition Si deposition SOAK PF &F STEP Dete	

14	Left click on the recipe's step, step menu shows up. Click "Edit Step", setting for this step will be displayed. DO NOT exceed 200W RF Power, or 1000mTorr pressure.	2 N2 puge 3 Suriac 5 Pumpe 5 Pumpe Cancel	
15	Click "Process"->"Recipes", click "Run" to start the process	Nungel Kanu Disch Statistics Name Disch Statistics Name Disch Statistics Statistics Disch Statistics Parge Disch Statistics<	
16	Enter wafer name again, the display will jump to each step and start.		
17	When process is done, an "Yellow Alert" will show up, display "End of process reached", click "Continue"		
18	Go back to "System"->"Pumping"	System • Process WUBilities System Menu Start Start COG N COG N We have a sword Exit West (1)	

Equipment Spec Oxford PECVD Plasmalab 80Plus.docx

19	Repeat "Stop"->"Vent" like previous step	Pumping or venting stopped Lid CLOSED Process interlock OK Cm gauge 7mTorr Vent Time Left Osecs EVACUATE STOP VENT O	Venting finished Lid CLOSED Process interlock FAULT Cm gauge Vent Time Left 0 secs EVACUATE STOP VENT O
20	Open chamber. Switch to "Chamber Up". Press two hoists.		
21	Take out the samples, put it on the side of the machine to cool down, close the chamber by switching to "Chamber Down". Press two hoists.		
22	Click "Stop"->"Evacuate" again, click "Cancel" if no samples	Load Wafer or pump chamber MJC Crists Wafer Hame(DK) His Wafer (CARCE) Extense Wafer Hame(DK) His Wafer (CARCE) Crists Wafer	It will still evacuate.
23	Click "User" on top	U PUMP CONTROL 100	

24	Click "Verify", and click "OK" to log out	PC 2000 VIS Current User Access Level Demonstration Enter Name Enter Password K X X
25	Tell staff you are done using	
	PECVD.	

- V. QUALITY
 - a. Substrates and thin film materials used in this machine are intended to provide a wide variety of alternatives to AggieFab users. No guarantee is made regarding effects of cross contamination due to particular substrates or targets in the history of operations for this tool on future users.

VI. SIGNATURES AND REVISION HISTORY

- a. Author of this document: Larry Rehn and Cheng-Chung Chang
- b. Author Title or Role: Technical Manager/Student Lab User
- c. Date: 5/2/2014
- d. Revision: Original Issue

Approvals:

Technical Manager Signature:_____

Date: _____

Revision History:

Revision	Author	Date
Original Issue	L. Rehn	5/2/2014
Rev A		
Rev B		
Rev C		

APPENDIX 1

Typical Deposition Rates for Silicon Oxide and Silicon Nitride Layers

Deposited Film/Layer	Recipe Name:	Gases: SiH4/N2 = 425 sccm
SiO2	SiO2 Deposition	N2O = 710 sccm
		T = 350°C, p = 1000 mTorr
		RF power = 20W
time (min)	thickness (nm)	Refractive Index
1	42.4	1.4
2	94.14	1.47
5	223.1	1.58
10	478.7	1.5

Deposited Film/Layer	Recipe Name:	Gases: SiH4/N2 = 120 sccm
SiNx	SiNx dep 13nm/min	N2 = 900 sccm
		T = 350°C,
		RF power = 60W
time (min)	thickness (nm)	Refractive Index
2	12.17	2.06
5	24.2	2
10	41.48	2.05
20	75.2	2.15

Deposited Film/Layer	Recipe Name:	Gases: SiH4/N2 = 125 sccm
Si3N4	Si3N4 Growth 7.2nm/min	N2 = 700 sccm
		T = 350°C,
		RF power = 15W
time (min)	thickness (nm)	Refractive Index
7	50	1.98
14	100	1.98
42	310	1.98